

<b>Notice of References Cited</b>		Application/Control No. 10/567,347	Applicant(s)/Patent Under Reexamination KATO ET AL.	
		Examiner ADAM A. ARCIERO	Art Unit 1795	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,074,785	06-2000	Dansui et al.	429/223
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 0831542A1	03-1998	Japan	Hideo et al.	
	O	JP 10270042A	10-1998	Japan	Sei et al.	
	P					
	Q					
	R					
	S					
	I					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IPDL PAJ JPO Machine Translation for Sei et al. (JP10-270042 A)
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.